

# RELIABILITY MONITOR

PROCESS: 2P, 2M, 0.6um, P2Cap, PdD, HP Vts, GOI, WJ BPSG, N+ESDII,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21352	A4	AUG '02	30219	0240	Stats	DC039494AA	LQFP	500	77	0
DS21352	A4	AUG '02	30219	0240	Stats	DC039494AA	LQFP	1000	77	0

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS21352	A4	FEB '03	31029	0242	ATP (Amkor, PI)	DK036653AA	LQFP	500	77	0
DS21352	A4	FEB '03	31029	0242	ATP (Amkor, PI)	DK036653AA	LQFP	1000	63	12
DS21352	A4	MAY '03	31401	0312	Stats	DC043465AA	LQFP	500	77	7

TOTALS:

FAIL RATE (Fits): 119    DEVICE HRS: 1.75E+08    19

# RELIABILITY MONITOR

PROCESS: D8R-2P2M,HPVt,NDROM,N+ESD,Laser N-sub,LOCOS:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2154	A2	NOV '02	30236	0230	Stats	DC102671AA	LQFP	500	80	2
DS2154	A2	NOV '02	30236	0230	Stats	DC102671AA	LQFP	1000	77	0

TOTALS:

FAIL RATE (Fits): 42 DEVICE HRS: 7.36E+07 2

# RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	500	80	0
DS1803	A2	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	500	80	0
DS1803	A2	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	1000	80	0
DS1803	A2	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	1000	80	0

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	APR '03	31261	0304	OSEP	DE322628AAB	SOIC	500	80	0
DS1803	A2	APR '03	31261	0304	OSEP	DE322628AAB	SOIC	500	80	0

TOTALS:

FAIL RATE (Fits): 4 DEVICE HRS: 2.26E+08 0

# RELIABILITY MONITOR

PROCESS: D6W-1P2M,HPVt,E2,TCZ PBL:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1100	A3	OCT '01	28535	0126	ATP (Amkor, PI)	DK114601AD	SOIC	336	77	0
DS1100	A3	JAN '02	28614	0132	ATP (Amkor, PI)	DK115002AK	SOIC	336	77	0
DS1100	A3	JAN '02	28614	0132	ATP (Amkor, PI)	DK115002AK	SOIC	1000	77	0
DS1100	A3	OCT '01	28535	0126	ATP (Amkor, PI)	DK114601AD	SOIC	1000	77	0
DS1100	A3	JAN '03	30770	0243	Carsem	DM242094AJC	SOIC	500	80	0
DS1100	A3	JAN '03	30770	0243	Carsem	DM242094AJC	SOIC	1000	80	0
DS1100	A3	JUL '02	30192	0230	OSEP	DE120202AFB	SOIC	500	80	0
DS1100	A3	JUL '02	30192	0230	OSEP	DE120202AFB	SOIC	1000	80	0

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1100	A3	APR '03	31254	0312	ATP (Amkor, PI)	DK242100AH	SOIC	500	80	0

TOTALS:

FAIL RATE (Fits): 3 DEVICE HRS: 3.34E+08 0

# RELIABILITY MONITOR

PROCESS: 1P, 2M, 0.8um, PdpIDiode, Ti/TiN M1+M2 , WJ BPSG, N+ESD II,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	500	80	0
DS1803	A2	OCT '02	30229	0234	ATP (Amkor, PI)	DK236047AA	SOIC	1000	80	0

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1803	A2	APR '03	31261	0304	OSEP	DE322628AAB	SOIC	500	80	0

TOTALS:

FAIL RATE (Fits): 8 DEVICE HRS: 1.13E+08 0

# RELIABILITY MONITOR

PROCESS: D6RL-1P1M,SILP1,LLVt,N+ESD PBL:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS80C320	C5	DEC '02	30259	0230	ATP (Amkor, PI)	DK240563AB	PDIP	500	77	0
DS80C320	C5	DEC '02	30259	0230	ATP (Amkor, PI)	DK240563AB	PDIP	1000	77	0

TOTALS:

FAIL RATE (Fits): 13 DEVICE HRS: 7.26E+07 0

# RELIABILITY MONITOR

PROCESS: D6S-1P1M,HPVt,N+ESD,TCN3 ALOCOS:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS2118M	C1-6	MAR '03	31035	0233	ATK (Amkor, K)	DN108304AB	SSOP	500	75	1
DS2118M	C1-6	MAR '03	31035	0233	ATK (Amkor, K)	DN108304AB	SSOP	1000	73	0

TOTALS:

FAIL RATE (Fits): 29 DEVICE HRS: 6.98E+07 1

# RELIABILITY MONITOR

PROCESS: 1P, 1M, 0.8um, PdpIDiode, Low Vts , N+ESDII, WJ BPSG,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232	C2-L	JAN '03	30758	0252	ATP (Amkor, PI)	DK235629AB	SOIC	500	80	0
DS1232	C2-L	JAN '03	30758	0252	ATP (Amkor, PI)	DK235629AB	SOIC	1000	80	0
DS1232	C2-L	JUL '02	30185	0111	OSEP	DE049638ADB	SOIC	500	79	0
DS1232	C2-L	JUL '02	30185	0111	OSEP	DE049638ADB	SOIC	1000	79	0

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1232	C2-L	APR '03	31302	0310	Carsem	DM304031AH	SOIC	500	80	0

TOTALS:

FAIL RATE (Fits): 5 DEVICE HRS: 1.88E+08 0

# RELIABILITY MONITOR

PROCESS: D8W-1P1M,HPVt,E2 LOCOS:GOI

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	JAN '03	30750	0249	Hana	DU218037AA	SOIC	500	80	0
DS1620	D1	JAN '03	30750	0249	Hana	DU218037AA	SOIC	1000	78	0
DS1621	A7	MAR '03	30966	0237	OSEP	DE106688AAB	SOIC	500	75	0
DS1621	A7	MAR '03	30966	0237	OSEP	DE106688AAB	SOIC	1000	75	0

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1620	D1	APR '03	31323	0310	NSEB	DJ232810AAB	SOIC	500	80	0
DS1620	D1	APR '03	31323	0310	NSEB	DJ232810AAB	SOIC	1000	80	0

TOTALS:

FAIL RATE (Fits): 4 DEVICE HRS: 2.21E+08 0

# RELIABILITY MONITOR

PROCESS: 1P, 1M, 1.2um, II Poly1 , TEOS Spacer,

STRESS: HIGH VOLTAGE LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1267	A1	AUG '02	30199	0237	Carsem	DM234023AF	TSSOP	500	79	0
DS1267	A1	AUG '02	30199	0237	Carsem	DM234023AF	TSSOP	1000	79	0

TOTALS: FAIL RATE (Fits): 12 DEVICE HRS: 7.45E+07 0

# RELIABILITY MONITOR

PROCESS: 1P, 1M, 1.2um, ZTC P1, Ndepletion ,Latell ZTC,TEOSsp,

STRESS: HIGH TEMP OP LIFE

PRODUCT	REV	MONITOR DATE	JOB NO	DATE CODE	ASSEMBLY FACILITY	LOT NO.	PACKAGE	READ POINT	QTY	FAILS
DS1233	A5-5	APR '03	31309	0311	Hana	DU321432DC	SOT223	500	80	0

TOTALS: FAIL RATE (Fits): 24 DEVICE HRS: 3.77E+07 0